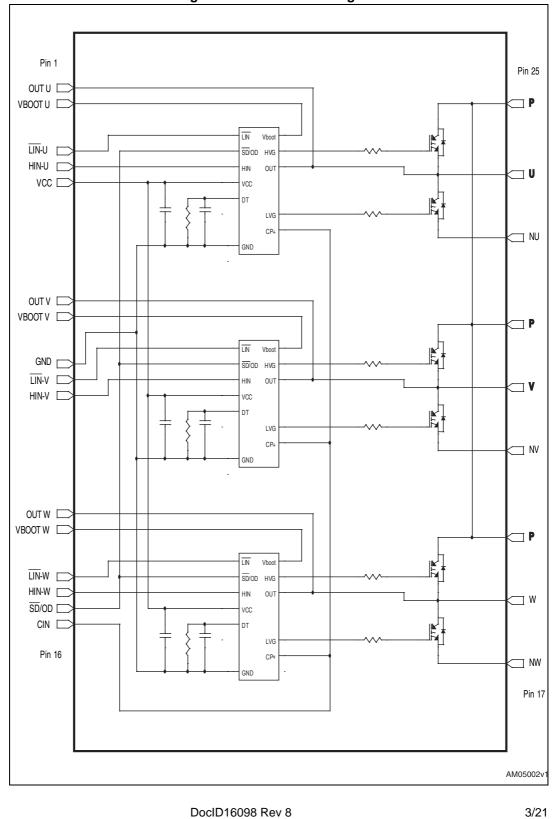
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1

## Internal block diagram and pin configuration



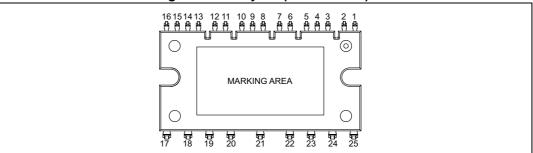


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Pin n°	Symbol	Description
1	OUTU	High-side reference output for U phase
2	V <sub>bootU</sub>	Bootstrap voltage for U phase
3	LINU	Low-side logic input for U phase
4	HINU	High-side logic input for U phase
5	V <sub>CC</sub>	Low voltage power supply
6	OUT <sub>V</sub>	High-side reference output for V phase
7	V <sub>boot V</sub>	Bootstrap voltage for V phase
8	GND	Ground
9	LINV	Low-side logic input for V phase
10	HINV	High-side logic input for V phase
11	OUT <sub>W</sub>	High-side reference output for W phase
12	V <sub>boot W</sub>	Bootstrap voltage for W phase
13	LINW	Low-side logic input for W phase
14	HIN <sub>W</sub>	High-side logic input for W phase
15	SD / OD	Shutdown logic input (active low) / open-drain (comparator output)
16	CIN	Comparator input
17	N <sub>W</sub>	Negative DC input for W phase
18	W	W phase output
19	Р	Positive DC input
20	N <sub>V</sub>	Negative DC input for V phase
21	V	V phase output
22	Р	Positive DC input
23	NU	Negative DC input for U phase
24	U	U phase output
25	Р	Positive DC input

Table 2. Pin description

### Figure 2. Pin layout (bottom view)





# 2 Electrical ratings

## 2.1 Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>PN</sub>	Supply voltage applied between P - $N_U$ , $N_V$ , $N_W$	450	V
V <sub>PN(surge)</sub>	Supply voltage (surge) applied between P - $N_U, \ N_V, \ N_W$	500	V
V <sub>CES</sub>	Each IGBT collector emitter voltage ( $V_{IN}^{(1)} = 0 V$ )	600	V
$\pm I_{C}^{(2)}$	Each IGBT continuous collector current at $T_{C} = 25 ^{\circ}\text{C}$	18	А
$\pm I_{CP}^{(3)}$	Each IGBT pulsed collector current	40	А
P <sub>TOT</sub>	Each IGBT total dissipation at $T_{C}$ = 25 °C	52	W
t <sub>scw</sub>	Short circuit withstand time, $V_{CE} = 0.5 V_{(BR)CES}$ T <sub>J</sub> = 125 °C, $V_{CC} = V_{boot}$ = 15 V, $V_{IN (1)}$ = 0 to 5 V	5	μs

#### Table 3. Inverter part

1. Applied between  $HIN_i$ ,  $\overline{LIN}_i$  and  $G_{ND}$  for i = U, V, W

2. Calculated according to the iterative formula:

$$I_{C}(T_{C}) = \frac{I_{j(max)} - I_{C}}{R_{thj-c} \times V_{CE(sat)(max)}(T_{j(max)}, I_{C}(T_{C}))}$$

3. Pulse width limited by max junction temperature

Symbol	Parameter	Min.	Max.	Unit						
V <sub>OUT</sub>	Output voltage applied between OUT <sub>U</sub> , OUT <sub>V</sub> , OUT <sub>W</sub> - GND	V <sub>boot</sub> - 21	V <sub>boot</sub> + 0.3	V						
V <sub>CC</sub>	Low voltage power supply	- 0.3	21	V						
V <sub>CIN</sub>	Comparator input voltage	- 0.3	V <sub>CC</sub> + 0.3	V						
V <sub>boot</sub>	Bootstrap voltage	- 0.3	620	V						
V <sub>IN</sub>	Logic input voltage applied between HIN, LIN and GND	- 0.3	15	V						
V <sub>SD/OD</sub>	Open drain voltage	- 0.3	15	V						
dV <sub>OUT</sub> /dt	Allowed output slew rate		50	V/ns						

### Table 4. Control part



Symbol	Parameter	Value	Unit				
V <sub>ISO</sub>	Isolation withstand voltage applied between each pin and heatsink plate (AC voltage, $t = 60 \text{ s}$ )	2500	V				
Тj	Power chips operating junction temperature	- 40 to 150	°C				
Т <sub>С</sub>	Module case operation temperature	- 40 to 125	°C				

Table 5. Total system

## 2.2 Thermal data

### Table 6. Thermal data

Symbol	Parameter	Value	Unit
P	Thermal resistance junction-case single IGBT	2.4	°C/W
R <sub>thJC</sub>	Thermal resistance junction-case single diode	5	0/10



## **3** Electrical characteristics

 $T_J = 25$  °C unless otherwise specified.

Currence al	Devenuetor	Test conditions		11		
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	Collector-emitter	$V_{CC} = V_{boot} = 15 \text{ V}, V_{IN}^{(1)} = 0 \div 5 \text{ V},$ $I_{C} = 12 \text{ A}$	-	2.2	2.75	
V <sub>CE(sat)</sub>	saturation voltage	$V_{CC} = V_{boot} = 15 \text{ V},$ $V_{IN}^{(1)} = 0 \text{ to } 5 \text{ V}, I_C = 12 \text{ A},$ $T_J = 125 \text{ °C}$	-	1.8		V
I <sub>CES</sub>	Collector-cut off current (V <sub>IN</sub> <sup>(1)</sup> = 0 "logic state")	$V_{CE} = 550$ V, $V_{CC} = V_{Boot} = 15$ V	-		150	μA
V <sub>F</sub>	Diode forward voltage	$V_{IN}^{(1)} = 0 V$ "logic state", $I_C = 12 A$	-		2.1	V
Inductive	load switching time and	energy				
t <sub>on</sub>	Turn-on time		-	300	-	
t <sub>c(on)</sub>	Crossover time (on)	V <sub>PN</sub> = 300 V,	-	150	-	Ī
t <sub>off</sub>	Turn-off time	$V_{PN} = 300 \text{ V},$ $V_{CC} = V_{boot} = 15 \text{ V},$	-	730	-	ns
t <sub>c(off)</sub>	Crossover time (off)	$V_{IN}^{(1)} = 0$ to 5 V,	-	170	-	Ť
t <sub>rr</sub>	Reverse recovery time	$I_{\rm C} = 12 \rm A$	-	60	-	Ī
Eon	Turn-on switching losses	(see <i>Figure 3</i> )	-	290	-	
E <sub>off</sub>	Turn-off switching losses		-	250	-	μJ

Table	7.	Inverter	part
-------	----	----------	------

1. Applied between HIN<sub>i</sub>,  $\overline{\text{LIN}}_{i \text{ and }} G_{ND}$  for i = U, V, W. ( $\overline{\text{LIN}}$  inputs are active-low).

Note:  $t_{ON}$  and  $t_{OFF}$  include the propagation delay time of the internal drive.  $t_{C(ON)}$  and  $t_{C(OFF)}$  are the switching time of IGBT itself under the internally given gate driving condition.



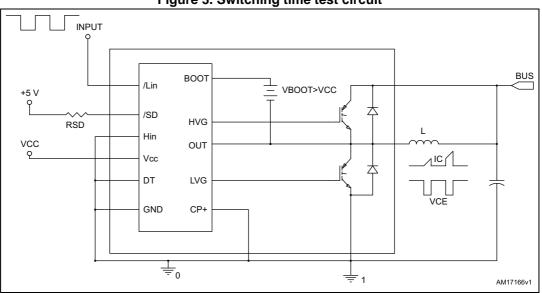


Figure 3. Switching time test circuit



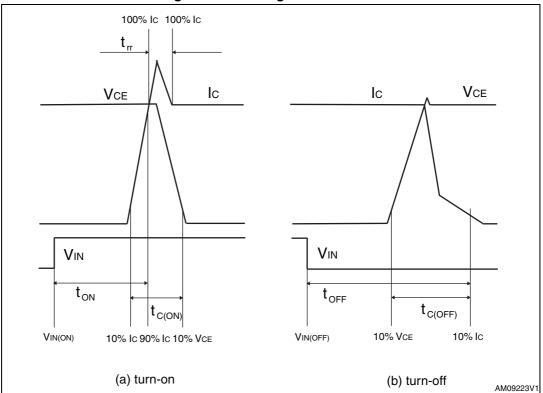




Figure 4: Switching time definition refers to HIN inputs (active high). For  $\overline{\text{LIN}}$  inputs (active low),  $V_{\text{IN}}$  polarity must be inverted for turn-on and turn-off.



## 3.1 Control part

## Table 8. Low voltage power supply ( $V_{CC}$ = 15 V unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>CC_hys</sub>	V <sub>CC</sub> UV hysteresis		1.2	1.5	1.8	V
V <sub>CC_thON</sub>	V <sub>CC</sub> UV turn ON threshold		11.5	12	12.5	V
$V_{CC_{thOFF}}$	V <sub>CC</sub> UV turn OFF threshold		10	10.5	11	V
I <sub>qccu</sub>	Undervoltage quiescent supply current				450	μA
I <sub>qcc</sub>	Quiescent current				3.5	mA
V <sub>ref</sub>	Internal comparator (CIN) reference voltage		0.5	0.54	0.58	V

### Table 9. Bootstrapped voltage ( $V_{CC}$ = 15 V unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>BS_hys</sub>	V <sub>BS</sub> UV hysteresis		1.2	1.5	1.8	V
V <sub>BS_thON</sub>	V <sub>BS</sub> UV turn ON threshold		11.1	11.5	12.1	V
V <sub>BS_thOFF</sub>	V <sub>BS</sub> UV turn OFF threshold		9.8	10	10.6	V
I <sub>QBSU</sub>	Undervoltage V <sub>BS</sub> quiescent current	$V_{BS} < 9 V$ $\overline{SD}/OD = 5 V; \overline{LIN} \text{ and}$ $HIN = 5 V; C_{IN} = 0$		70	110	μA
I <sub>QBS</sub>	V <sub>BS</sub> quiescent current	$V_{BS} = 15 V$ $\overline{SD}/OD = 5 V; \overline{LIN} \text{ and}$ $HIN = 5 V; C_{IN} = 0$		210	300	μA
R <sub>DS(on)</sub>	Bootstrap driver on resistance	LVG ON		120		Ω

### Table 10. Logic inputs (V<sub>CC</sub> = 15 V unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>il</sub>	Low logic level voltage		0.8		1.1	V
V <sub>ih</sub>	High logic level voltage		1.9		2.25	V
I <sub>HINh</sub>	HIN logic "1" input bias current	HIN = 15 V	110	175	260	μA
I <sub>HINI</sub>	HIN logic "0" input bias current	HIN = 0 V			1	μA
I <sub>LINI</sub>	LIN logic "1" input bias current	$\overline{\text{LIN}} = 0 \text{ V}$	3	6	20	μA
I <sub>LINh</sub>	LIN logic "0" input bias current	LIN = 15 V			1	μA
I <sub>SDh</sub>	SD logic "0" input bias current	<u>SD</u> = 15 V	30	120	300	μA
I <sub>SDI</sub>	SD logic "1" input bias current	$\overline{SD} = 0 V$			3	μA
Dt	Dead time	see Figure 7		600		ns



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>ib</sub>	Input bias current	V <sub>CIN</sub> = 1 V	-		3	μA
V <sub>ol</sub>	Open-drain low-level output voltage	I <sub>od</sub> = 3 mA	-		0.5	V
t <sub>d_comp</sub>	Comparator delay	$\overline{SD}$ /OD pulled to 5 V through 100 k $\Omega$ resistor	-	90	130	ns
SR	Slew rate	$C_L = 180 \text{ pF}; \text{ R}_{pu} = 5 \text{ k}\Omega$	-	60		V/µsec
t <sub>sd</sub>	Shut down to high / low side driver propagation delay	$V_{OUT} = 0$ , $V_{boot} = V_{CC}$ , $V_{IN} = 0$ to 3.3 V	50	125	200	
t <sub>isd</sub>	Comparator triggering to high / low side driver turn-off propagation delay	Measured applying a voltage step from 0 V to 3.3 V to pin CIN	50	200	250	ns

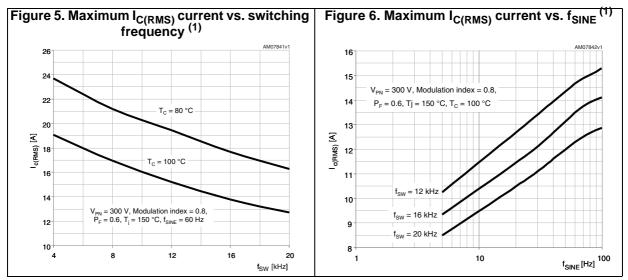
Table	e 11. Sense comparator ch	aracteristics (V <sub>CC</sub> = 15 V un	less oth	erwise s	pecified	)

### Table 12. Truth table

Condition	Logic input (V <sub>I</sub> )			Output		
Condition	SD/OD	LIN	HIN	LVG	HVG	
Shutdown enable half-bridge tri-state	L	х	х	L	L	
Interlocking half-bridge tri-state	Н	L	Н	L	L	
0 ''logic state" half-bridge tri-state	Н	н	L	L	L	
1 "logic state" low side direct driving	Н	L	L	н	L	
1 "logic state" high side direct driving	н	н	н	L	н	

Note: X: don't care





1. Simulated curves refer to typical IGBT parameters and maximum  $\mathrm{R}_{\mathrm{thj-c.}}$ 



## 3.2 Waveform definitions

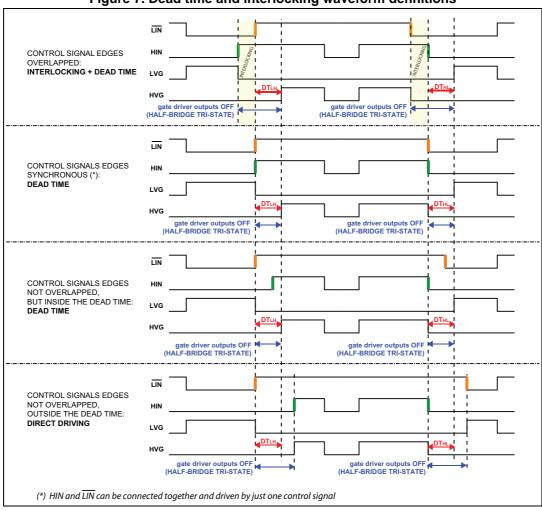


Figure 7. Dead time and interlocking waveform definitions



## 4 Smart shutdown function

The STGIPS20K60 integrates a comparator for fault sensing purposes. The comparator has an internal voltage reference Vref connected to the inverting input, while the non-inverting input, available on pin (CIN), can be connected to an external shunt resistor in order to implement a simple over-current protection function. When the comparator triggers, the device is set in shutdown state and both its outputs are set to low-level leading the halfbridge in tri-state. In the common overcurrent protection architectures the comparator output is usually connected to the shutdown input through a RC network, in order to provide a mono-stable circuit, which implements a protection time that follows the fault condition. Our smart shutdown architecture allows to immediately turn-off the output gate driver in case of overcurrent, the fault signal has a preferential path which directly switches off the outputs. The time delay between the fault and the outputs turn-off is no more dependent on the RC values of the external network connected to the shutdown pin. At the same time the DMOS connected to the open-drain output (pin SD/OD) is turned on by the internal logic which holds it on until the shutdown voltage is lower than the logic input lower threshold (Vil). Finally the smart shutdown function provides the possibility to increase the real disable time without increasing the constant time of the external RC network.



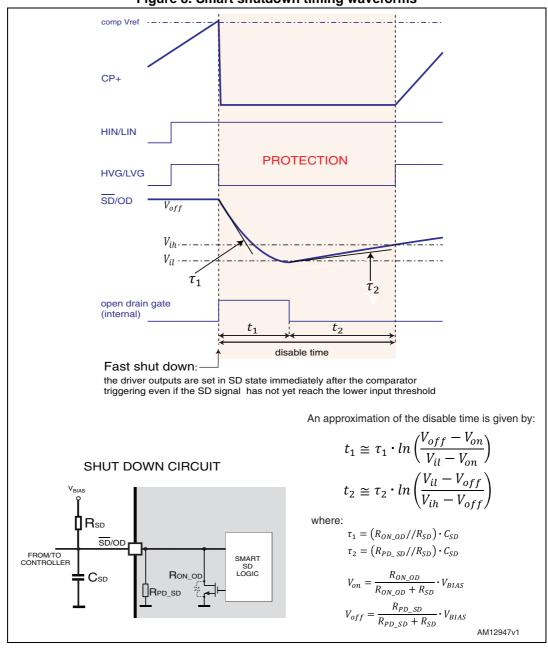
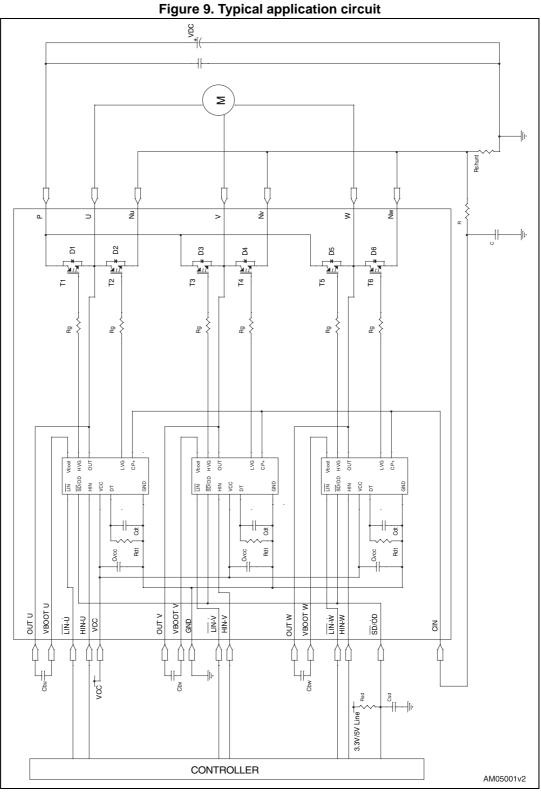


Figure 8. Smart shutdown timing waveforms

Please refer to Table 11 for internal propagation delay time details.



#### **Application information** 5







### 5.1 Recommendations

- Input signal HIN is active high logic. A 85 kΩ (typ.) pull-down resistor is built-in for each high side input. If an external RC filter is used, for noise immunity, pay attention to the variation of the input signal level.
- Input signal  $\overline{\text{LIN}}$  is active low logic. A 720 k $\Omega$  (typ.) pull-up resistor, connected to an internal 5 V regulator through a diode, is built-in for each low side input.
- To prevent the input signals oscillation, the wiring of each input should be as short as possible.
- By integrating an application specific type HVIC inside the module, direct coupling to MCU terminals without any opto-coupler is possible.
- Each capacitor should be located as nearby the pins of IPM as possible.
- Low inductance shunt resistors should be used for phase leg current sensing.
- Electrolytic bus capacitors should be mounted as close to the module bus terminals as possible. Additional high frequency ceramic capacitor mounted close to the module pins will further improve performance.
- The SD/OD signal should be pulled up to 5 V / 3.3 V with an external resistor (see Section 4: Smart shutdown function for detailed info).

Symbol	Parameter	Conditions	Value			Unit
Symbol	Farameter	Conditions	Min.	Тур.	Max.	Unit
V <sub>PN</sub>	Supply Voltage	Applied between P-Nu,Nv,Nw		300	400	V
V <sub>CC</sub>	Control supply voltage	Applied between V <sub>CC</sub> -GND	13.5	15	18	V
V <sub>BS</sub>	High side bias voltage	Applied between $V_{BOOTI}$ -OUT <sub>i</sub> for i = U,V,W	13		18	V
t <sub>dead</sub>	Blanking time to prevent Arm-short	For each input signal	1			μs
f <sub>PWM</sub>	PWM input signal	-40°C < T <sub>c</sub> < 100°C -40°C < T <sub>j</sub> < 125°C			20	kHz
т <sub>с</sub>	Case operation temperature				100	°C

#### Table 13. Recommended operating conditions

For further details refer to AN3338.





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## 6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK<sup>®</sup> is an ST trademark.

Please refer to dedicated technical note TN0107 for mounting instructions.

## 6.1 SDIP-25L package information

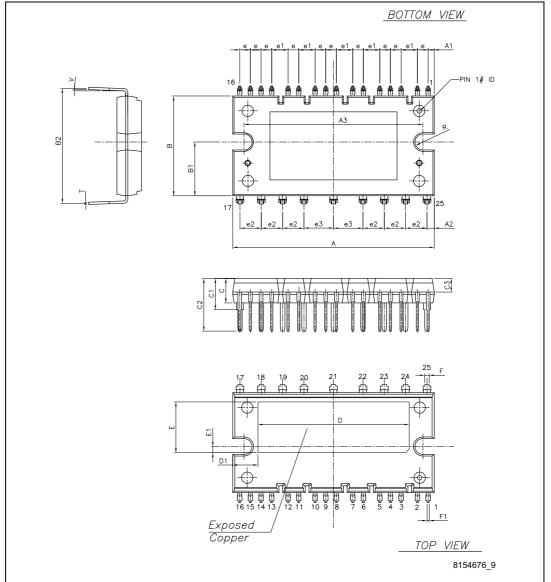


Figure 10. SDIP-25L package outline

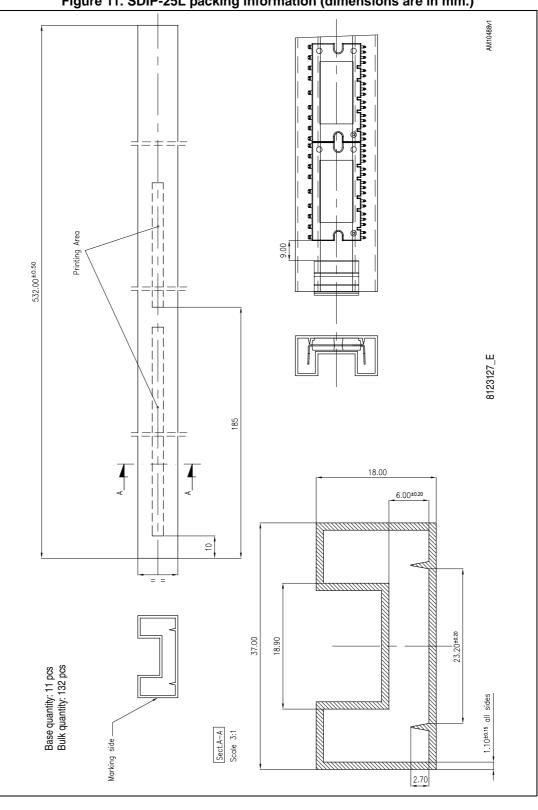


	Table 14. SDIP	P-25L mechanical data			
Dim. mm					
	Min.	Тур.	Max.		
А	43.90	44.40	44.90		
A1	1.15	1.35	1.55		
A2	1.40	1.60	1.80		
A3	38.90	39.40	39.90		
В	21.50	22.00	22.50		
B1	11.25	11.85	12.45		
B2	24.83	25.23	25.63		
С	5.00	5.40	6.00		
C1	6.50	7.00	7.50		
C2	11.20	11.70	12.20		
C3	2.90	3.00	3.10		
е	2.15	2.35	2.55		
e1	3.40	3.60	3.80		
e2	4.50	4.70	4.90		
e3	6.30	6.50	6.70		
D		33.30			
D1		5.55			
E		11.20			
E1		1.40			
F	0.85	1.00	1.15		
F1	0.35	0.50	0.65		
R	1.55	1.75	1.95		
Т	0.45	0.55	0.65		
V	0°		6°		

Table 14. SDIP-25L mechanical data



## 6.2 SDIP-25L packing information



### Figure 11. SDIP-25L packing information (dimensions are in mm.)



# 7 Revision history

Date	Revision	Changes	
10-Aug-2009	1	Initial release	
01-Jul-2010	2	Document status promoted from preliminary to datasheet. Updated package mechanical data ( <i>Section 6: Package information</i> ). Minor text changes to improve readability.	
23-Sep-2010	3	Updated: <i>Table 3, 5, 10</i> and <i>Table 11</i> . Modified: <i>Figure 5</i> and <i>Figure 6</i> .	
03-May-2011	4	Updated title with SLLIMM <sup>™</sup> in cover page, added SDIP-25L tube dimensions <i>Figure 10: SDIP-25L package outline</i> .	
04-Nov-2011	5	Updated title with SLLIMM <sup>™</sup> (small low-loss intelligent molded module) IPM, 3-phase inverter - 18 A, 600 V short-circuit rugged IGBT in cover page and SDIP-25L mechanical data <i>Table 14 on page 17, Figure 10 on page 17.</i>	
28-Aug-2012	6	Modified: Min. and Max. value <i>Table 4 on page 5</i> . Updated: <i>Figure 11 on page 19</i> . Added: <i>Figure 12 on page 20</i> .	
02-May-2013	7	Modified: Figure 3 on page 8 and Figure 8 on page 14.	
21-Apr-2015	8	Text and formating changes throughout document. Updated <i>Figure 2: Pin layout (bottom view)</i> Updated <i>Table 7: Inverter part</i> Updated <i>Figure 10: SDIP-25L package outline</i> Updated and renamed <i>Section 6: Package information</i> (was Package mechanical data)	

Table 15. Document	revision history
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